## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | WONG ET AL. | Examiner | Art Unit | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,112,974	09-2000	Nishiura et al.	228/180.5
*	В	US-2004/0041008	03-2004	Mochida, Toru	228/180.5
*	С	US-2004/0152292	08-2004	Babinetz et al.	438/617
*	D	US-2004/0104477	06-2004	Fujisawa, Hiromi	257/738
*	E	US-6,182,885	02-2001	Nishiura et al.	228/180.5
*	F	US-6,815,836	11-2004	Ano, Kazuaki	257/784
*	G	US-2004/0080056	04-2004	Lim et al.	257/784
*	Н	US-2003/0166333	09-2003	Takahashi, Takuya	438/617
*	ı	US-2002/0047213	04-2002	Komiyama et al.	257/777
*	٦	US-2004/0115918	06-2004	Kanda et al.	438/612
*	к	US-6,495,773	12-2002	Nomoto et al.	174/260
*	L	US-2005/0189567	09-2005	Fujisawa, Hiromi	257/200
*	М	US-6,962,282	11-2005	Manansala, Michael	228/180.5

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYYY format are publication dates. Classifications may be US or foreign.